Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/646,554	SCHOWTKA, ALEXANDER K.
Examiner	Art Unit
Blake E. Betz	2672

SEARCHED				
Class	Subclass	Date	Examiner	
345	619	2/2/2005	ВВ	
	620	2/1/2005	ВВ	
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INTERFERENCE SEARCHED				
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